INTEGRATED CIRCUITS



Product specification Supersedes data of 1999 Jun 23 1999 Sep 17



Philips Semiconductors

Quad GTL/GTL+ to LVTTL/TTL bidirectional non-latched translator

GTL2005

FEATURES

- Operates as a quad GTL/GTL+ sampling receiver or as a LVTTL/TTL to GTL/GTL+ driver
- Quad bidirectional bus interface
- Live insertion/extraction permitted
- Latch-up protection exceeds 500 mA per JESD78
- ESD protection exceeds 2000 V HBM per JESD22-A114, and 1000 V CDM per JESD22-CC101

DESCRIPTION

The GTL2005 is a quad translating transceiver designed for 3.3 V system interface with a GTL/GTL⁺ bus.

The direction pin allows the part to function as either a GTL to TTL sampling receiver or as a TTL to GTL interface.

QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS T _{amb} = 25°C		TYPICAL B to A A to B		
t _{PLH} t _{PHL}	Propagation delay An to Bn or Bn to An	$C_L = 50 \text{ pF}; V_{CC} = 3.3 \text{ V}$	2.1 1.9	4.1 4.3	ns	
C _{IN}	Input capacitance DIR	$V_I = 0 V \text{ or } V_{CC}$	3.0	3.0	pF	
C _{I/O}	I/O pin capacitance	Outputs disabled; $V_{I/O} = 0 V \text{ or } 3.0 V$	7.8	4.5	рF	

ORDERING INFORMATION

PACKAGES	TEMPERATURE RANGE	ORDER CODE	DWG NUMBER
14-Pin Plastic TSSOP Type II	-40°C to +85°C	GTL2005 PW DH	SOT402-1

PIN DESCRIPTION

PIN NUMBER	SYMBOL	NAME AND FUNCTION
1	DIR	Direction control input
2, 3, 5, 6	A0 – A3	Data inputs/outputs (A side, GTL)
13, 12, 10, 9	B0 – B3	Data inputs/outputs (B side, TTL)
4	GTLREF	GTL reference voltage
7, 8, 11	GND	Ground (0 V)
14	V _{CC}	Positive supply voltage

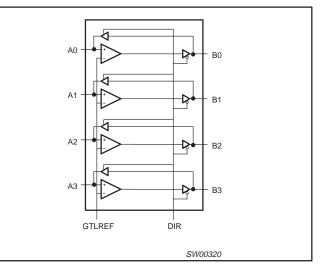
FUNCTION TABLE

INPUT	INPUT/OUTPUT					
DIR	В	А				
Н	Inputs	Bn = An				
L	An = Bn	Inputs				

H = HIGH voltage level

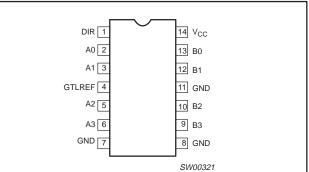
L = LOW voltage level

LOGIC SYMBOL





PIN CONFIGURATION



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ABSOLUTE MAXIMUM RATINGS¹

In accordance with the Absolute Maximum System (IEC 134); voltages are referenced to GND (ground = 0 V).

SYMBOL	PARAMETER	TEST CONDITIONS	RATING	UNIT
V _{CC}	DC supply voltage		-0.5 to +4.6	V
l _{IK}	DC input diode current	V ₁ < 0	-50	mA
M	DC input voltage ³	A port	-0.5 to +7.0	V
VI	DC Input voltage	B port	-0.5 to +4.6	V
I _{OK}	DC output diode current	V _O < 0	-50	mA
V	DC output voltage ³	Output in Off or High state; A port	-0.5 to +7.0	V
Vo	DC oulput voltage	Output in Off or High state; B port	-0.5 to +4.6	V
1	Current into any output in the LOW state	A port	128	mA
IOL	Current into any output in the LOW state	B port	80	mA
I _{OH}	Current into any output in the HIGH state	A port	-64	mA
T _{stg}	Storage temperature range		-60 to +150	°C

NOTES:

 Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "Recommended Operating Conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction

temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C. 3. The input and output negative voltage ratings may be exceeded if the input and output clamp current ratings are observed.

RECOMMENDED OPERATING CONDITIONS¹

SYMBOL	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V _{CC}	Supply voltage		0		3.6	V
M	Termination voltage	GTL	1.14	1.2	1.26	V
V _{TT}	Termination voltage	GTL+	1.35	1.5	1.65	v
M	Supply voltogo	GTL	0.74	0.8	0.87	V
V _{REF}	Supply voltage	GTL+	0.87	1.0	1.10	v
M	In the veltage	A port 0 0	V _{TT}	V		
VI	Input voltage	Except A port	0		5.5	v
M		A port	V _{REF} + 50 mV			V
VIH	HIGH-level input voltage	Except A port	2			v
M		A port			$V_{REF} - 50 \text{ mV}$	V
VIL	LOW-level input voltage	Except A port			0.8	v
I _{ОН}	HIGH-level output current	B port			-12	mA
		A port			40	mA
IOL	LOW-level output current	B port			12	mA
T _{amb}	Operating free-air temperature range		-40		85	°C

NOTE:

1. Unused control inputs must be held HIGH or LOW to prevent them from floating.

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DC ELECTRICAL CHARACTERISTICS

Over recommended operating conditions. Voltages are referenced to GND (ground = 0 V).

				LIMITS				
SYMBOL	PARAMETER	TEST CONDITIONS	-40	UNIT				
			MIN	TYP ¹	MAX	1		
M	P. nort	$V_{CC} = 3.0$ to 3.6 V; $I_{OH} = -100 \ \mu A$	V _{CC} -0.2			V		
V _{OH}	B port	$V_{CC} = 3.0 V_{;} I_{OH} = -12 mA$	2.0			1 ^v		
M	A port	$V_{CC} = 3.0 V_{;} I_{OL} = 40 \text{ mA}$			0.4	V		
V _{OL}	B port	V _{CC} = 3.0 V; I _{OL} = 12 mA			0.8	V		
	Control inputs	$V_{CC} = 3.6 \text{ V}; \text{ V}_{I} = V_{CC} \text{ or GND}$			± 1			
	A port	$V_{CC} = 3.6 \text{ V}; \text{ V}_{I} = \text{V}_{TT} \text{ or GND}$			± 1	1		
I _I		$V_{CC} = 0 \text{ or } 3.6 \text{ V}; \text{ V}_{I} = 5.5$			10	μΑ		
	B port	$V_{CC} = 3.6 \text{ V}; \text{ V}_{I} = V_{CC}$			± 1			
		$V_{CC} = 3.6 \text{ V}; V_{I} = 0 \text{ V}$			-5	1		
I _{OFF}	A port	$V_{CC} = 0 \text{ V}; \text{V}_{\text{I}} \text{ or } \text{V}_{\text{O}} = 0 \text{ to } 4.5 \text{ V}$			± 100	μA		
I _{EX}	B port	V _O = 5.5 V; V _{CC} = 3.0 V		50	125	μΑ		
I _{CC}	A or B port	$V_{CC} = 3.6 \text{ V}; \text{V}_{\text{I}} = \text{V}_{CC} \text{ or GND}; \text{ I}_{\text{O}} = 0$			3	mA		
ΔI_{CC}^3	B port or control inputs	$V_{CC} = 3.6 \text{ V}; \text{ V}_{I} = V_{CC} - 0.6 \text{ V}$			500	μΑ		
Cl	Control inputs	$V_{I} = 3.0 V \text{ or } 0$		3		pF		
0	B port	$V_0 = 3.0 V \text{ or } 0$	1	7.8				
C _{IO}	A port	$V_0 = V_{TT} \text{ or } 0$	1	4.5		pF		

NOTES:

1. All typical values are measured at $V_{CC} = 3.3 \text{ V}$ and $T_{amb} = 25^{\circ}C$. 2. The input and output voltage ratings may be exceeded if the input and output current ratings are observed. 3. This is the increase in supply current for each input that is at the specified TTL voltage level rather than $V_{CC \text{ or } GND}$.

AC CHARACTERISTICS (3.3 V ±0.3 V RANGE)

			LIMITS (GTL) LIMITS (GT				MITS (GTL	+)	
SYMBOL	PARAMETER	WAVEFORM	V _{CC}	= 3.3 V ± 0 / _{REF} = 0.8 V	.3 V	V _{CC}	= 3.3 V ±0 / _{REF} = 1.0 V	.3 V /	UNIT
			MIN	TYP ¹	MAX	MIN	TYP ¹	MAX	
t _{PLH} t _{PHL}	Bn to An	1		2.1 1.9	2.3 2.6		2.1 1.9	2.3 2.6	ns
t _{PLH} t _{PHL}	An to Bn	2		4.1 4.4	5.4 5.4		4.2 3.8	5.3 4.8	ns

NOTES:

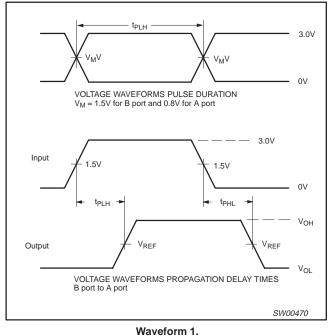
1. All typical values are at V_{CC} = 3.3 V and T_{amb} = 25° C.

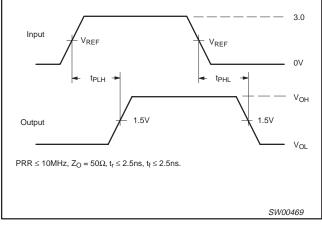
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AC WAVEFORMS

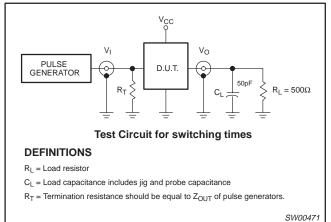
 V_M = 1.5 V at V_{CC} \geq 3.0 V, ~V_M = V_{CC}/2 at V_{CC} \leq 2.7 V for B ports and control pins V_M = V_{Ref} for A ports

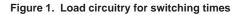




Waveform 2.

TEST CIRCUIT





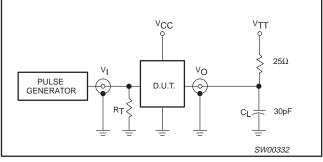
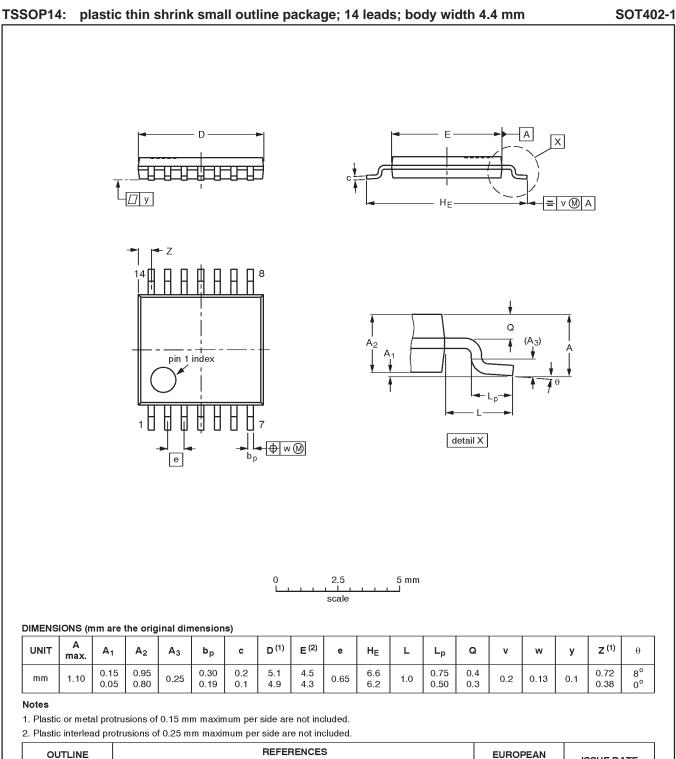


Figure 2. Load circuit for A outputs

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Product specification



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NOTES

Data sheet status

Data sheet status	Product status	Definition ^[1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.
Product specification	Production	This data sheet contains final specifications. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.

[1] Please consult the most recently issued datasheet before initiating or completing a design.

Definitions

Short-form specification — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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